



Examiner-Pro offers product and test engineers everything they need to characterize new ICs and test programs, quickly ramp up production at OSATs and identify and diagnose yield excursions when they occur. Examiner-Pro turns standard test data files like STDF, PCM and 100+ other formats into comprehensible reports, and enables you to drill down into the data interactively for root-cause analysis.

Examiner-Pro can analyze datalog files directly and can query data that has been inserted into the Test Data Repository (TDR option), a relational database built on MariaDB. Coupled with the TDR, Examiner-Pro offers powerful productivity features, including the multi-variable characterization wizard for corner-case analysis, genealogy/die trace for correlation between e-test, wafer sort and final test, and fast, flexible queries and reports on huge datasets. Examiner-Pro also serves as a client for Yield-Man. Allowing you to automate the yield management process at some point in the future, you'll preserve your investment and utilize the same user interface.

Examiner-Pro is incredibly easy to use, fast, and requires no special training. You can download the free trial version and be analyzing your test data in minutes. The majority of our 7500+ users are product, test, and process engineers from fabless, IDM, OSAT, and ATE companies. Engineers choose Examiner-Pro because it allows them to analyze huge amounts of test data quickly and reliably. Saving time on the analysis gives users more time to focus on important critical issues.

### Benefits

Thousands of users attest to the value of Examiner-Pro in helping them get their job done faster and allowing more time for high-value activities. And since it acts as a common user interface for all Galaxy products, using Examiner-Pro helps prepare you for automated yield management with Yield-Man and automated outlier removal with PAT-Man.

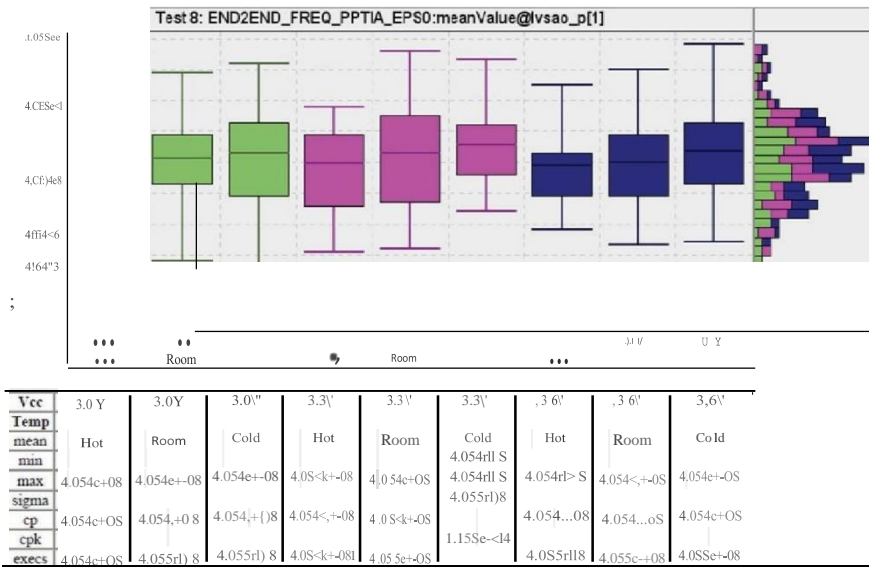
### FEATURES AND BENEFITS

#### Standard and custom reports:

- GLOBAL INFORMATION: Tester, lot, operator information
- YIELD INFORMATION: Good parts, failing parts, parts retested
- TEST SUMMARY: Cp, Cpk, mean, sigma, skew fail count, etc.
- TEST HISTOGRAM: Quickly view your test distribution
- PARAMETRIC TEST WAFER MAP: Analyze the test gradient on your wafer to investigate process problems
- WAFER MAP: See all dice tested in production, binning, time info
- FLEXIBLE INPUT FORMAT: Supports 150+ different tester platforms and data formats, including STDF, GDF, ATDF, WAT, PCM, and CSV
- PARAMETRIC TREND CHARTS: See how test results evolve over time in production
- PARETO REPORTS: Cpk of tests, failures, binning
- CORRELATION REPORTS: Conduct gage R/R studies
- RELIABILITY AND SHIFT ANALYSIS: Measure parametric shifts based on time and temperature

#### Features enabled by TDR option:

- FAST RDB-BASED ANALYSIS: Analyze large data sets stored in MariaDB database eliminating the need to maintain raw datafiles
- MULTI-VARIABLE CHARACTERIZATION WIZARD: Perform corner-case analysis across multiple process corners, voltages, temperatures, frequencies, etc.
- GENEALOGY AND DIE TRACE: Correlate parametrics between sort and e-test and between final and sort



New multi-variable characterization wizard creates intuitive composite reports in minutes, showing the impact of temperature, voltage, process and any other variables.

It's no wonder that Examiner-Pro has become a de facto industry standard and is used internally by all the major ATE companies and many OSATs.

### New Productivity Features in Version 7.8

Examiner-Pro Version 7.8 adds a number of new features that enhance your productivity:

Multi-Window Dock Support: attach and detach report windows

Stacked Bar Charts by Site for Paretos: shows breakdown by site

On the Fly Reports: build customized final reports by selecting interactive charts and tables that you wish to include

Session Saving: save state of session before exiting and then continue where you left off with settings and on-the-fly reports preserved

Box Plot Outliers: shows data outside of selected range as outliers

Extracting Test Conditions & Levels from Test Program (DTR Records)

## SYSTEM REQUIREMENTS

### PC Hardware

- CPU: Intel or AMD dual-core x86 or IA-64, 1.2 GHz min
- Memory: 16 GB recommended, 4 GB minimum
- Disk space: 100 MB for application plus additional space for data files

### Operating System

- Windows 10 (64 bit recommended)
- Linux, RHEL / Centos 7.x or higher

## EXAMINATOR APPLICATIONS

Examiner is used for a broad range of applications in engineering and production processes including:

- PVT corner case analysis
- Test time optimization
- Test program limit tuning
- Root cause analysis
- Tester correlation studies
- Subcontractor qualification
- Quality and reliability analysis

For the latest product information, call us or visit: <https://www.galaxysemi.com/>

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